Abstracts

FDTD characterization of waveguide-probe structures

E. Tentzeris, M. Krumpholz, N. Dib, Jong-Gwan Yook and L.P.B. Katehi. "FDTD characterization of waveguide-probe structures." 1998 Transactions on Microwave Theory and Techniques 46.10 (Oct. 1998, Part I [T-MTT]): 1452-1460.

The finite-difference time-domain (FDTD) technique is applied in the calculation of the S-parameters of diode mounting and waveguide-probe structures. The influence of the critical geometrical design parameters on the coupling of the coplanar feedline probe to the waveguide is investigated. A waveguide absorber based on analytic Green's functions is used to minimize the reflections over a wide band of frequencies.

❑ Return to main document.